Shannon's Entropy

H(
$$\Sigma_n$$
) = [E [log $\frac{1}{\Sigma_n(x)}$]

 $\times \sim \Sigma_n [U, w]$:

 $\times \sim \Sigma_n [U, w]$:

TM Mon input w

 $\times \in \{a_0\}_1^m$

H(U_n) = V_n

"most" random dist.

"most" random string

Universal Sevendomizedton

Given a BPP algorithm $M(x, r)$,

for every $x \in \{a_1\}_1^m$,

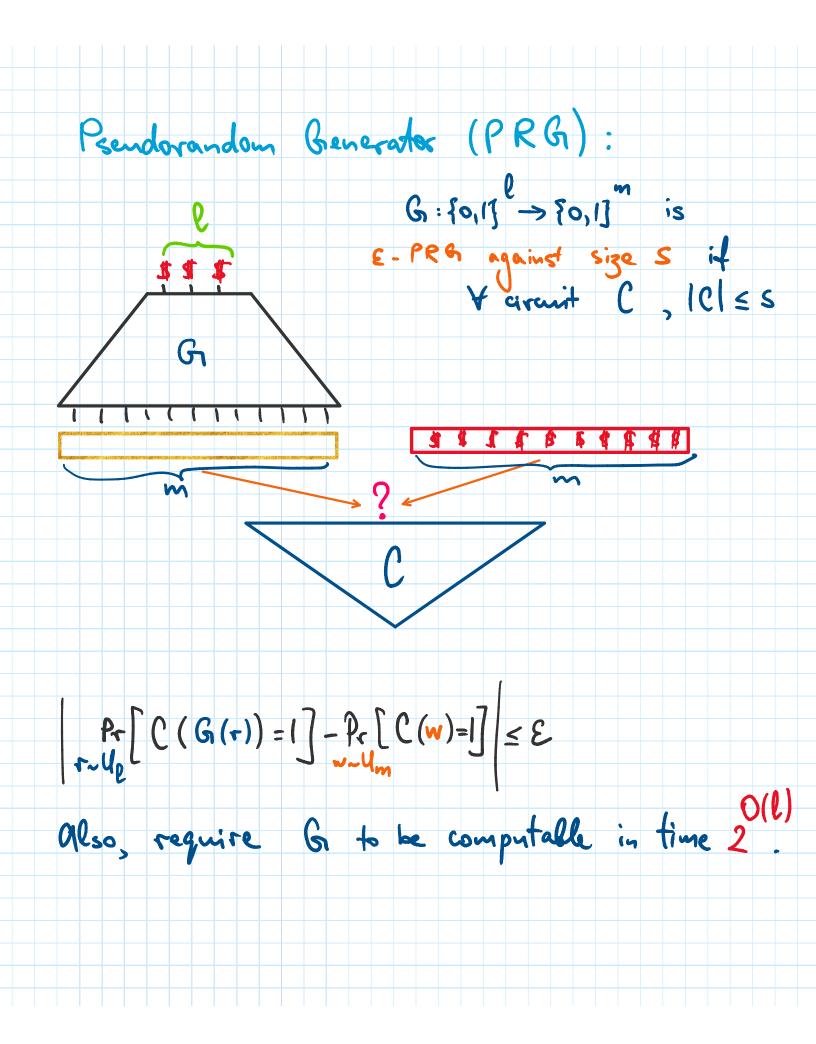
want to estimate

 $P_n [M(x, r) \ accepts] + E$
 $1 \sim U_m [M(x, r) \ accepts] + E$
 $1 \sim U_m [M(x, r) \ accepts] + E$

```
with little (no) randomness.
Idea: For X, find some & (of small support),
Pr [M(x,r) accepts] - Pr [M(x,r) accepts] < E
                         compute "brute force"

in time poly (|x|, |supp(Dm)|)
  Xm E-fools M(x, \cdot) for a given x
 More ambitiously: E-fool M(x,.) for all x
Observe: M(x,r) in time t(|x|)

\Rightarrow \forall x, \exists circuit C_x(r) of size O(t(|x|))
 Hence, sufficient to \varepsilon-fool all circuits of size S \leq O(t).
```



To estimate Pr[C(w)=1] compute Pr[C(G(r))=1]in det. time $2^{O(l)}$ poly (|C|). Goal: $\varepsilon - PRG G: \{O_1\}^{\ell} \rightarrow \{O_1\}^{m}$ for $\ell \leq O(\log(m/\epsilon))$. Non-constructively, such a Grexists. Open Question: Construct (any nontrivial) such G. Why is it so hard to construct a PRB ? (because it implies circuit lower bounds!) Observation: Suppose have PRG G: 80,11 -> 80,11 seavre against size m circuits.

Define f: {0,113 -> {0,113}: C 0 :1 7 2 450.11 Ca(2)

$$f(x) = \begin{cases} 0 & \text{if } \exists e \in \text{PolI}^{\ell} & G(z) |_{\text{Ell}} = x \\ 1 & \text{otherwise} \end{cases}$$
Note: (1) $f(G(z)) = 0$, $\forall z \in \text{FolI}^{\ell}$

(2) $\text{Pr} \left[f(x) = 1 \right] \geqslant \frac{1}{2}$

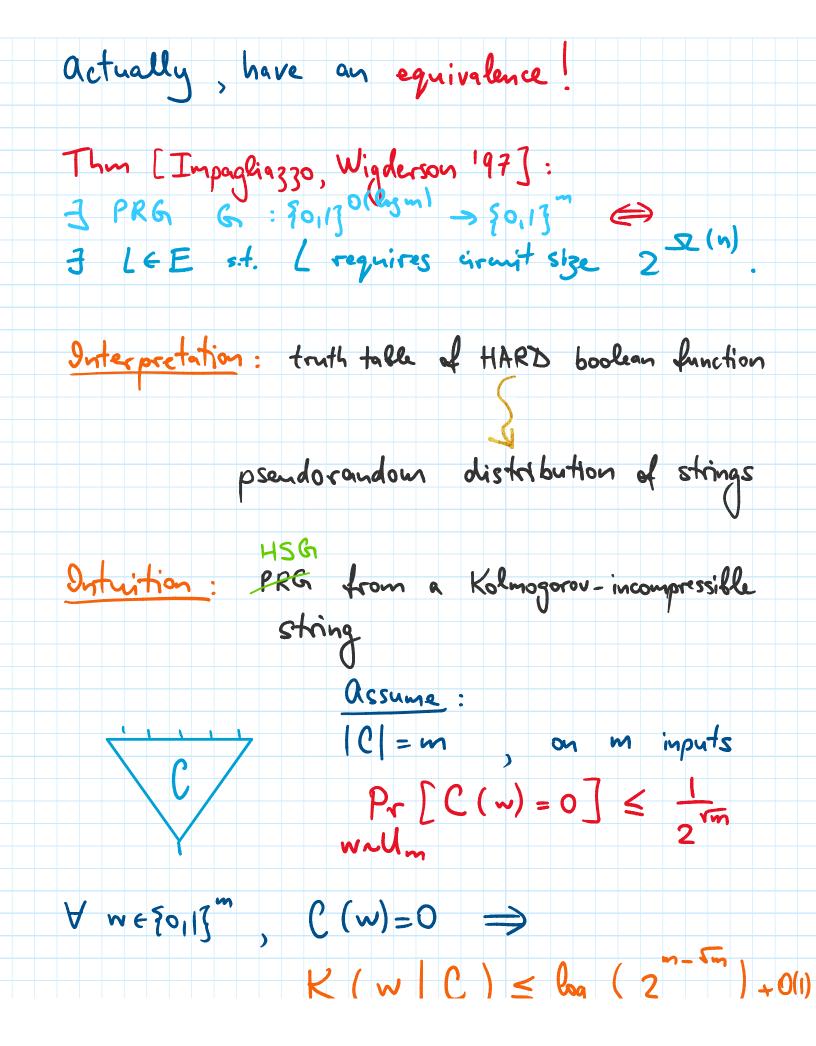
Hence, $f \notin \text{Size}[m]$

For $\ell \in O(\log_{1} m)$, $f \notin \text{Size}[2]$

but $f \in \text{Time}[2]$

(Recoll: $\text{PIT} \in P \Rightarrow \text{circuit lower bounds for NEXP} \text{ or permanent.}$)

(Recoll: $\text{PIT} \in P \Rightarrow \text{circuit lower bounds for permanent.}$)



 $K(w|C) \leq \log_{2}(2^{m-1m}) + O(1)$ $\leq m - \sqrt{m} + O(1)$ So, C must accept a string of high (conditional) Kolmogorov complexity! Colm)

K suffices, but still ... Want a much more efficient compression of W if a PRG based on w fails to fool some C Want a "small" ciscuit for W. Yao's distinguisher -> predicter idea:

Yao's distinguisher -> predictor idea: Suppose a circuit C: {0,17 -> {0,13 E-distinguishes a distribution & from Um: Pr[C(8m)=1] - Pr[C(Um)=1] > E Hybrid Argument:

Sefine distribution $H' = \Delta_m U_m$ i m_i [sample $W \sim \Delta_m$; Output i-length prefix of W_i followed by M_i unif. rand.

bits] Pr[C(Dm)=1]-Pr[C(Um)=1]

Sample b; bits..., by uniformly at random.

If
$$C(z_1,...,z_{i-1},b_i,b_{i+1},...,b_m)=1$$

then output b;
else output 7b;

(Exercise.)

NW PRG

For any $f: ?0,117 \rightarrow ?0,117$

define $C: ?0,117 \rightarrow ?0,117$

Endistinguishes $C: ?0,117 \rightarrow ?0,117$

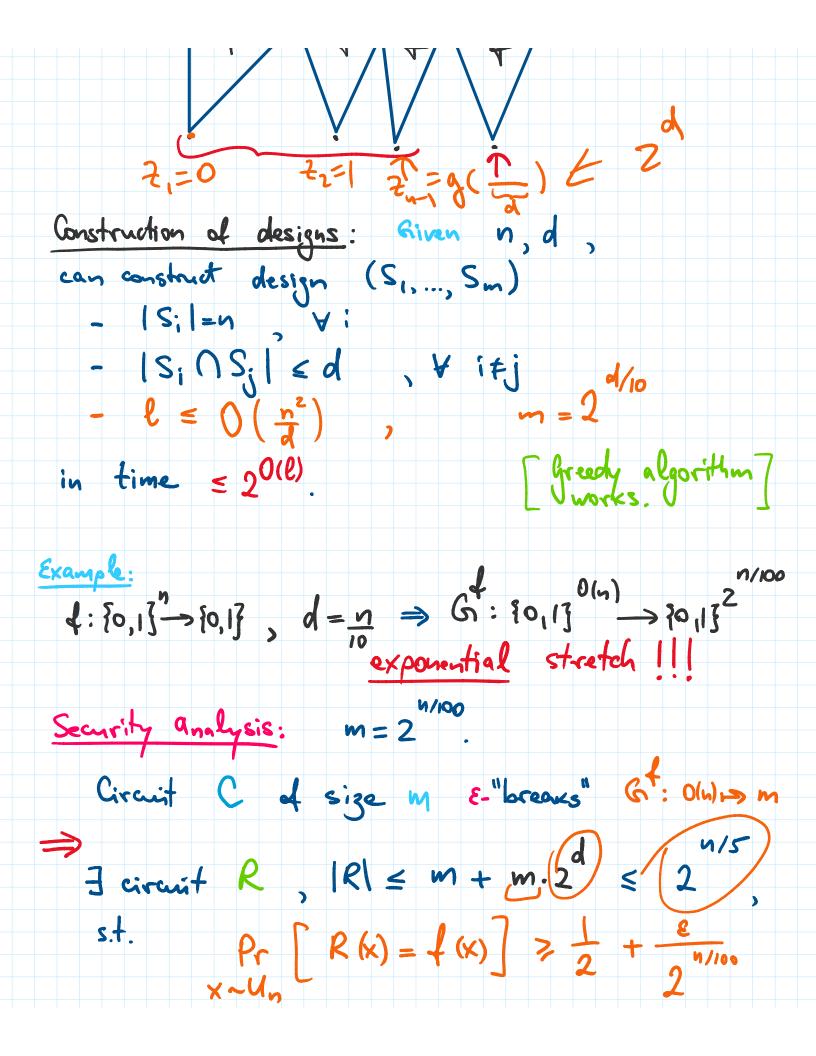
Endistinguishes $C: ?0,117 \rightarrow ?0,117$

Endistinguishes $C: ?0,117 \rightarrow ?0,117$

E-distinguishes Gr from U_{n+1} ,
then a circuit of size $\approx |C|$ computes f on $\geq 1 + \epsilon$ inputs. That is "easy" on average. Why? Upshot: It is very hard on average

PRG but with only 1-bit stretch. How to get a PRG with a letter stretch? Idea 1: Direct Product Grenerator &: $G(x_1, x_2, ..., x_k) = x_1 x_2 ... x_k \{(x_i) \} \{(x_k) ... \} \{(x_k) \}$ Gr $(x_1, x_2, ..., x_k) = x_1 x_2 ... x_k \{(x_i) | \{k_2\} ... \} (x_k)$ where each $x_i \in \{0,1\}^n$. Still secure if f is 'very hard" on average.

Stretch: n.k > n.k+k still very poor! Odea 2: "Derandamize" & P Generator above, using designs: $S = (S_1, S_2, ..., S_m)$ each $|S_i| = n$ $\forall i \neq j, |S_i| \leq d$ each $|S_i| \leq \{1, 2, ..., l\}$ minimize NW PRG G: {0,13 -> {0,13 m}: $G^{\ell}(z) = \ell(z|_{S_{1}}) \dots \ell(z|_{S_{m}})$ The state of the s



Why? Need 4: {0,13" > {0,13 exponentially hard on average ! Corollary [Nisan, Wigderson]:

E has a language of exp. average-ease hardness

BPP=P. Thin [IW, STV]: E has a language of exp. average-ease hardness E has a language of exp. worst-case hardness. Lusing list-decodable ECC]

Lusing 415T-decodate ECT SKT-raile Corollary: E requires Gircuit size) 2

BPP = P. also, MA = NP

Other hardness-randomness trade-effs can be also proved, e.g., Thun [BFNW]: EXP & Poly Size → ∀ ε>0, BPP ⊆ i.o.-Time [2"]. Some applications Easy Witness Lemma [IKW]: Suppose NEXP \subseteq Poly Size.

Then \forall $L \in NTime [2^n]$ with verifier $V : \{0,1\}^n \times \{0,1\}^2 \rightarrow \{0,1\}$ ₩ x € L of sufficiently large length n

```
    ∀ x ∈ L of sufficiently large length n
    ∃ circuit T: {0,13 → {0,13 of size ≤ n}

                                                               s.t. V(x, truth table (T)) = 1.
Proof: Suppose not.

3 L & NTime [2]
                              H d > 0

3 infinitely many x \( \xi \) \( \xi 
Oversimplifying:
(1) Can handeterministically guess superpoly-hard t.t.
               (2) Via [BFNW], can derandomize
                                                                            MA = NSUBEXP.
                (3) NEXP & Poly Size
                                           => EXP = Poly Size
                                           => EXP = MA [Karp-Lipton]
              (4) EXP = MA = NSUBEXP
```

(5) NEXP = Poly Size ⇒ NSUBEXP ⊆ Size [n x]
for a fixed constant x >0. [using universal TMs] $(4)+(5) \Longrightarrow$ EXP & Size [n]. Contradiction ∃ K>0 , (via diagonalization).

Corollary: NEXP S Poly Size > NEXP = MA.

Summary

Randonness is useful

- for algorithms for reasoning about complexity classes

Pseudo-randomness = Craint lower bounds

Pseudo-rav	domness vs	Le	arning		
			0		
•	• •				